## Notice of References Cited Application/Control No. 10/762,473 Examiner Charles H Nolan, Jr. Applicant(s)/Patent Under Reexamination OHMURA, AKIRA Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,701,845	03-2004	Ohmura, Akira	101/484
*	В	US-6,058,249	05-2000	Matsuda et al.	358/1.14
*	С	US-2001/0009456	07-2001	Tanaka, Hiroshi	355/77
*	D	US-5,638,497	06-1997	Kimber et al.	358/1.15
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 10191453 A	07-1998	Japan	TAKI, MINORU	H04Q 07/38
*	0	EP 0856972 A	08-1998	Japan	Shiota et al.	H04L 29/06
*	Ρ	JP 11146308 A	05-1999	Japan		B41J 29/38
*	σ	JP 2002366636 A	12-2002	Japan	TAKEUCHI et al.	G06F 17/60
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V	·				
	w					
	×					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.